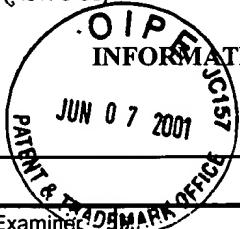


Form PTO-1449
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Patent and Trademark Office

Atty Docket 0756-1603

Serial No. 08/841,644



INFORMATION DISCLOSURE STATEMENT

JUN 07 2001

Applicants: Shunpei YAMAZAKI et al.

Filing Date: April 30, 1997

Group Art Unit: 2813

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*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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				Applicants: Shunpei YAMAZAKI et al.			
				Filing Date: April 30, 1997		Group Art Unit: 2813	
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05/31/2001							